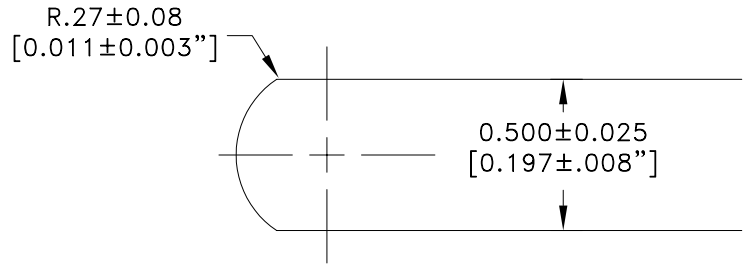


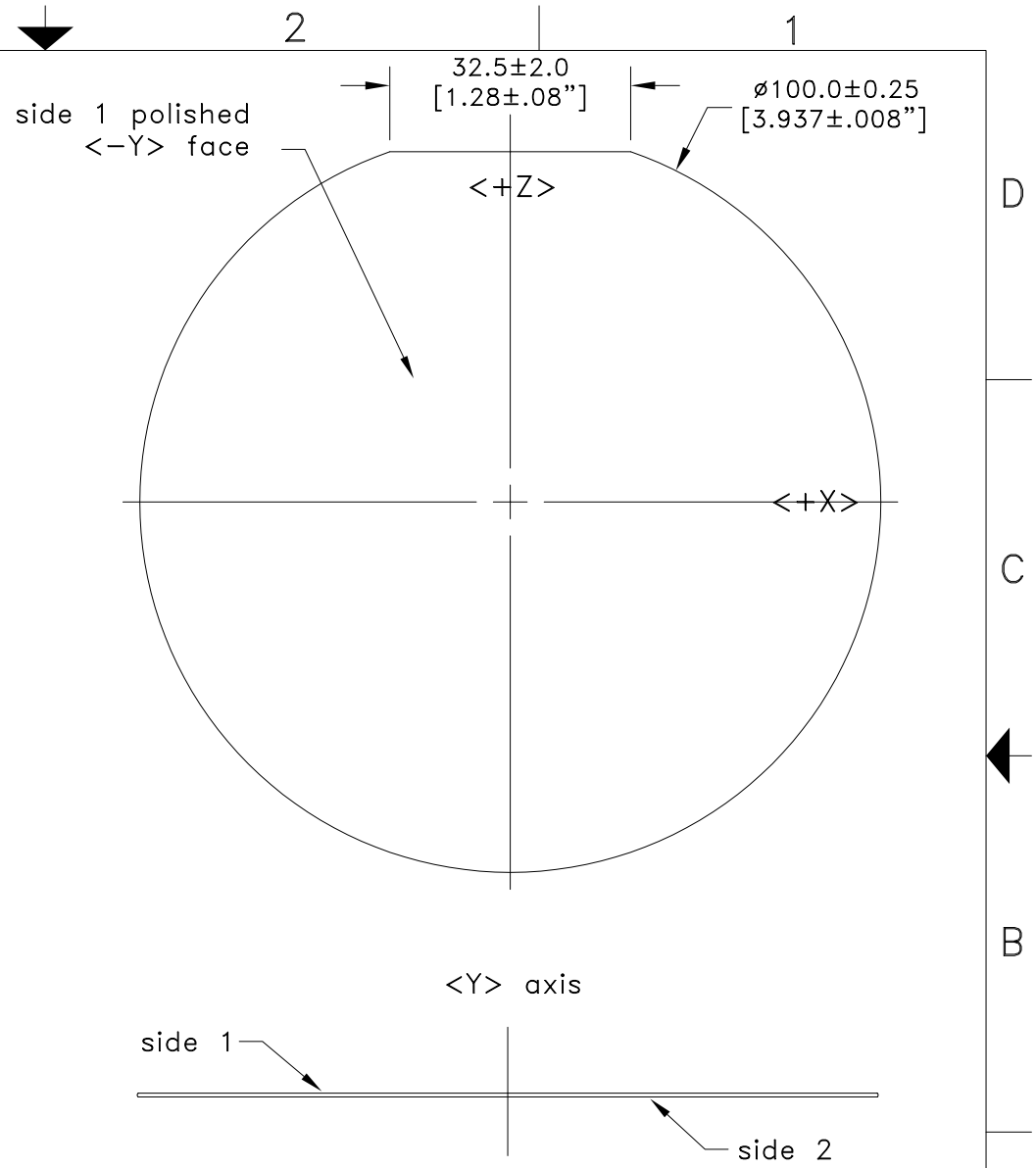
Rev	Description	Appd.	Date
C	Update per EO 13466	gs	11/10/03


- Notes:
- 1.0 Orientations
 - 1.1 Wafer surface is normal $\langle -Y \rangle \pm 0.25^\circ$
 - 1.2 Flats
 - Primary flat is normal to $\langle +Z \rangle \pm 0.25^\circ$.
 - 2.0 Edge
 - 2.1 All edges rounded with $R0.27 \pm 0.08\text{mm}$.
 - 2.2 No chips greater than 0.5mm in penetration and 1.0mm in length.
 - 3.0 Surfaces
 - 3.1 Side 1 $\langle -Y \rangle$ face
 - Polished 10-5 scratch-dig with 1mm edge exclusion.
 - No pits or scratches visible with reflected light and unaided eye.
 - 3.2 Side 2 $\langle +Y \rangle$ face
 - Ground, $Ra\ 0.50\mu\text{m}-0.70\mu\text{m}$.
 - 4.0 Flatness
 - 4.1 Warp $< 50\mu\text{m}$.
 - 4.2 TTV $< 25\mu\text{m}$.

For Reference Only



Wafer Edge Detail, 40X



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Material: Lithium Niobate	DR. Scholz	10/08/03	 Crystal Technology, Inc. An EPCOS Company
Unless otherwise specified, dimensions in mm	CHK.		
Tolerances		APPD.	Title: LNY4 100ø x 0.5mm, $\langle -Y \rangle$ Po/Gr, +Z FLT
Inches	Millimeters	Wafer Code:	Size: A
.X ± 0.1 .XX ± 0.01 .XXX ± 0.005 .XXXX ± 0.0020	X ± 0.5 .X ± 0.25 .XX ± 0.1 .XXX ± 0.05	Customer Approval:	Dwg. No: 97-01030-01
Angles ± 0.5°	DO NOT SCALE DRAWING	Scale: 1:1	Rev: C
		Sheet 1 of 1	